

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	177	tube with recognition with pattern	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:25
L2	181	tube with recognition with (pattern or waveform)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:27
L3	29	tube near4 recognition with (pattern or waveform)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:30
L4	322	tube near4 recognition	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:33
L5	6	("3202761").URPN.	USPAT	OR	OFF	2007/07/23 12:32
L6	47	tube near4 recognition and camera	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:34
L7	15	tube near4 recognition and camera and inspect\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:40

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L8	868	tube near4 inspect\$4 and camera	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:41
L9	188	tube near4 inspect\$4 and camera and (opening with tube)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:42
L10	30	tube near4 inspect\$4 and camera with (opening with tube)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 13:04
L11	68	tube near4 inspect\$4 and cameras with tube	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/23 13:52
L12	87	382/142.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 13:59



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Results for "((((tube <near> inspect*)<in>metadata))<and>('cameras'<in>metadata))"

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A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

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((((tube <near> inspect*)<in>metadata))<and>('cameras'<in>metadata))

☐ Check to search only within this results setDisplay Format: ☒ Citation ☐ Citation & Abstract

» Key

IEEE JNL IEEE Journal or Magazine

IET JNL IET Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IET CNF IET Conference Proceeding

IEEE STD IEEE Standard

[Select All](#) [Deselect All](#)

- ☐ 1. Inspection of continuously moving metallic tubes by artificial vision: moc results
Truchetet, F.; Jender, H.; Lew-Yan-Voon, L.F.C.;
[Industrial Electronics, Control and Instrumentation, 1994. IECON '94., 20th Int Conference on](#)
Volume 2, 5-9 Sept. 1994 Page(s):749 - 754 vol.2
Digital Object Identifier 10.1109/IECON.1994.397879
[AbstractPlus](#) | Full Text: [PDF\(356 KB\)](#) IEEE CNF
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- ☐ 2. Using computer vision for the automatic inspection and alignment of tele
Yerem, G.C.; Koch, D.B.;
[SoutheastCon, 2002. Proceedings IEEE](#)
5-7 April 2002 Page(s):67 - 72
Digital Object Identifier 10.1109/2002.995560
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